

# **FDW2503N**

# **Dual N-Channel 2.5V Specified PowerTrench® MOSFET**

### **General Description**

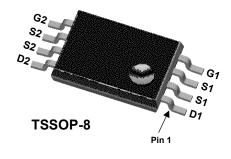
This N-Channel 2.5V specified MOSFET is a rugged gate version of Fairchild's Semiconductor's advanced PowerTrench process. It has been optimized for power management applications with a wide range of gate drive voltage (2.5V-12V).

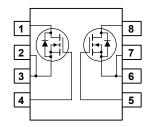
### **Applications**

- Load switch
- · Motor drive
- DC/DC conversion
- · Power management

### **Features**

- 5.5 A, 20 V.  $R_{DS(ON)} = 0.021 \Omega @ V_{GS} = 4.5 V$  $R_{DS(ON)} = 0.035 \Omega @ V_{GS} = 2.5 V$
- Extended V<sub>GSS</sub> range (±12V) for battery applications
- · Low gate charge
- High performance trench technology for extremely low R<sub>DS(ON)</sub>
- Low profile TSSOP-8 package





Absolute Maximum Ratings T<sub>A</sub>=25°C unless otherwise noted

Symbol	Parameter		Ratings	Units
V <sub>DSS</sub>	Drain-Source Voltage		20	V
V <sub>GSS</sub>	Gate-Source Voltage		±12	V
I <sub>D</sub>	Drain Current - Continuous	(Note 1a)	5.5	Α
	- Pulsed		30	
P <sub>D</sub>	Power Dissipation	(Note 1a)	1.0	W
		(Note 1b)	0.6	
$T_J$ , $T_{STG}$	Operating and Storage Junction Temperature Range		-55 to +150	°C

### **Thermal Characteristics**

$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	(Note 1a)	125	°C/W
		(Note 1b)	208	

**Package Marking and Ordering Information** 

Device Marking	Device	Reel Size	Tape width	Quantity
2503N	FDW2503N	13"	12mm	3000 units

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Char	acteristics			I	I	I
BV <sub>DSS</sub>	Drain–Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$	20			V
<u>ΔBV<sub>DSS</sub></u> ΔT <sub>J</sub>	Breakdown Voltage Temperature Coefficient	I <sub>D</sub> = 250 μA,Referenced to 25°C		14		mV/°C
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	$V_{DS} = 16 \text{ V}, \qquad V_{GS} = 0 \text{ V}$			1	μΑ
I <sub>GSSF</sub>	Gate-Body Leakage, Forward	V <sub>GS</sub> = 12 V, V <sub>DS</sub> = 0 V			100	nA
I <sub>GSSR</sub>	Gate–Body Leakage, Reverse	V <sub>GS</sub> = -12 V V <sub>DS</sub> = 0 V			-100	nA
On Char	acteristics (Note 2)					
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	0.6	0.8	1.5	V
$\Delta V_{GS(th)} \over \Delta T_J$	Gate Threshold Voltage Temperature Coefficient	I <sub>D</sub> = 250 μA,Referenced to 25°C		-3.2		mV/°C
$R_{DS(on)}$	Static Drain-Source	$V_{GS} = 4.5 \text{ V}, \qquad I_D = 5.5 \text{ A}$		17	21	mΩ
On–Re	On–Resistance	$V_{GS} = 2.5 \text{ V}, \qquad I_D = 4.2 \text{ A}$		24	35	
		$V_{GS} = 4.5 \text{ V}, I_D = 5.5 \text{A}, T_J = 125 ^{\circ}\text{C}$		23	34	
I <sub>D(on)</sub>	On-State Drain Current	$V_{GS} = 4.5 \text{ V}, \qquad V_{DS} = 5 \text{ V}$	30			Α
<b>g</b> FS	Forward Transconductance	$V_{DS} = 5 V$ , $I_{D} = 5.5 A$		26		S
Dynamic	Characteristics					
C <sub>iss</sub>	Input Capacitance	V <sub>DS</sub> = 10 V, V <sub>GS</sub> = 0 V, f = 1.0 MHz		1082		pF
Coss	Output Capacitance			277		pF
C <sub>rss</sub>	Reverse Transfer Capacitance			130		pF
Switchin	ng Characteristics (Note 2)					
t <sub>d(on)</sub>	Turn-On Delay Time	$V_{DD} = 10 \text{ V}, \qquad I_D = 1 \text{ A},$		8	20	ns
t <sub>r</sub>	Turn-On Rise Time	$V_{GS} = 4.5 \text{ V}, \qquad R_{GEN} = 6 \Omega$		8	27	ns
$t_{d(off)}$	Turn-Off Delay Time			24	38	ns
t <sub>f</sub>	Turn-Off Fall Time			8	16	ns
Q <sub>g</sub>	Total Gate Charge	$V_{DS} = 10 \text{ V}, \qquad I_{D} = 5.5 \text{ A},$		12	17	nC
Q <sub>gs</sub>	Gate-Source Charge	V <sub>GS</sub> = 4.5 V		2		nC
$Q_{gd}$	Gate-Drain Charge			3		nC
Drain-S	ource Diode Characteristics	and Maximum Ratings				
Is	Maximum Continuous Drain-Source	Diode Forward Current			0.83	Α
$V_{SD}$	Drain–Source Diode Forward Voltage	$V_{GS} = 0 \text{ V},  I_S = 0.83 \text{ A}  \text{(Note 2)}$		0.7	1.2	V

<sup>1.</sup>  $R_{\theta JA}$  is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins.  $R_{\theta JC}$  is guaranteed by design while  $R_{\theta CA}$  is determined by the user's board design.

a) R $_{\rm \theta JA}$  is 125°C/W (steady state) when mounted on a 1 inch² copper pad on FR-4. b) R $_{\rm \theta JA}$  is 208 °C/W (steady state) when mounted on a minimum copper pad on FR-4.

<sup>2.</sup> Pulse Test: Pulse Width < 300μs, Duty Cycle < 2.0%

# **Typical Characteristics**

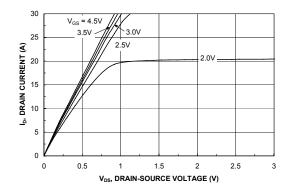


Figure 1. On-Region Characteristics.

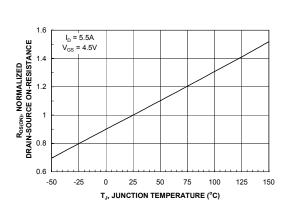


Figure 3. On-Resistance Variation with Temperature.

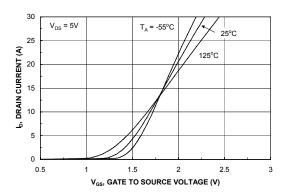


Figure 5. Transfer Characteristics.

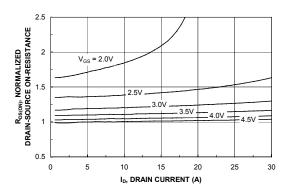


Figure 2. On-Resistance Variation with Drain Current and Gate Voltage.

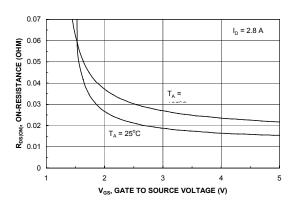


Figure 4. On-Resistance Variation with Gate-to-Source Voltage.

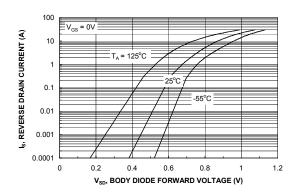
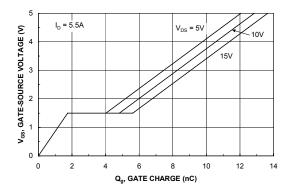


Figure 6. Body Diode Forward Voltage Variation with Source Current and Temperature.

# **Typical Characteristics**



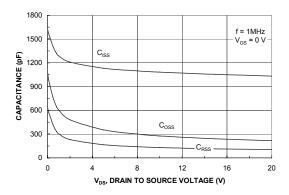
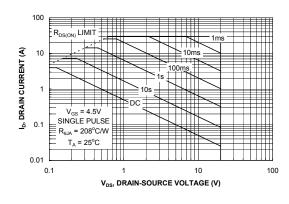


Figure 7. Gate Charge Characteristics.





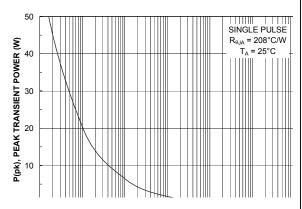


Figure 9. Maximum Safe Operating Area.

Figure 10. Single Pulse Maximum Power Dissipation.

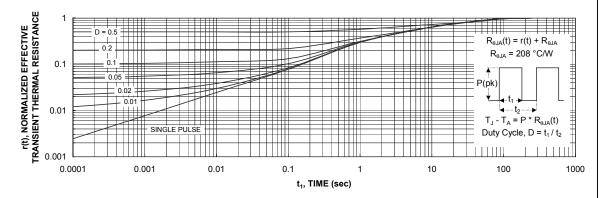


Figure 11. Transient Thermal Response Curve.

Thermal characterization performed using the conditions described in Note 1b. Transient thermal response will change depending on the circuit board design.

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